Notice of References Cited Application/Control No. 10/542,318 Applicant(s)/Patent Under Reexamination YONEZAWA, KEITARO Examiner Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,604,738 B2	08-2003	Haruna, Yosuke	269/309
*	В	US-2004/0046302 A1	03-2004	Bernhard et al.	269/309
*	С	US-2006/0055099 A1	03-2006	Haruna, Yosuke	269/309
*	D	US-2006/0049568 A1	03-2006	Yonezawa et al.	269/309
*	E	US-6,095,509 A	08-2000	Yonezawa, Keitaro	269/309
*	F	US-6,024,354 A	02-2000	Yonezawa, Keitaro	269/309
*	G	US-6,527,266 B1	03-2003	Yonezawa et al.	269/309
*	H	US-2006/0033255 A1	02-2006	Yonezawa et al.	269/309
*	ı	US-2006/0049569 A1	03-2006	Yonezawa, Keitaro	269/309
	J	US-			
	К	US-			
		US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					-
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.